

PIC18FXX2 Rev. B2 Silicon/Data Sheet Errata

The PIC18FXX2 parts you have received conform functionally to the Device Data Sheet (DS39564B), except for the anomalies described below.

Microchip intends to address all issues listed here in future revisions of the PIC18FXX2 silicon.

The following silicon errata apply only to PIC18FXX2 devices with these Device/Revision IDs:

Part Number	Device ID	Revision ID
PIC18F242	00 0100 100	00100
PIC18F252	00 0100 000	00100
PIC18F442	00 0100 101	00100
PIC18F452	00 0100 001	00100

The Device IDs (DEVID1 and DEVID2) are located at addresses 3FFFFEh:3FFFFFh in the device's configuration space. They are shown in hexadecimal in the format "DEVID2 DEVID1".

1. Module: Program Memory (Code Protection)

Enabling code protection for any program memory block will also enable write protection for that block. This would prevent even legitimate self-write attempts by the microcontroller, such as those used in a bootloader, in any code-protected block.

Work around

Do not enable code protection for any block that may need to be rewritten using the table write instructions.

Date Codes that pertain to this issue:

All engineering samples and devices with date codes up to and including 0211 (Year 2002, Work Week 11).

2. Module: Program Memory

Data corruption may occur during a table write operation if a peripheral interrupt also occurs. This happens only when the interrupt enable bit (PIE or INTCON register) for the corresponding interrupt has also been set.

Work around

Before executing any table write instructions, disable ALL peripheral interrupts. This is best done by clearing all interrupt enable bits in the three Interrupt Control registers (INTCON, INTCON2 and INTCON3) and both Peripheral Interrupt Enable registers (PIE1 and PIE2). After the table write is complete, restore all INTCON and PIE registers to their pre-instruction state.

Date Codes that pertain to this issue:

All engineering and production devices.

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3. Module: Data EEPROM

When reading the data EEPROM, the contents of the EEDATA register may become corrupted in the second instruction cycle after the RD bit (EECON1<0>) is set. The actual contents of the EEPROM remains unaffected.

Work around

To ensure the integrity of the contents of EEDATA, the register must be read in the instruction immediately following the setting of the RD bit. Use the MOVF or MOVFF instructions to do this (see Example 1).

Additionally, all interrupts must be disabled prior to the read instruction sequence. Interruptions of the sequence may have the same result of altering the contents of EEDATA.

EXAMPLE 1: SUGGESTED SEQUENCE FOR READING EEDATA

```
•  
•  
BCF    INTCON,GIEH ;disable interrupts  
                ;if using interrupts  
BSF    EECON1,RD   ;start the read operation  
MOVF   EEDATA,W    ;move the data out of  
                ;EEDATA  
BSF    INTCON,GIEH ;enable interrupts  
                ;if using interrupts  
•  
•
```

Date Codes that pertain to this issue:

All engineering and production devices.

4. Module: Interrupts

Under certain conditions, the use of dual priority interrupts may cause a program instruction to be skipped entirely. This has only been observed when both of the following apply:

- Both high and low interrupts are enabled, and
- A high priority asynchronous interrupt occurs in the following cycle after any low priority interrupts.

The event causes the stack to get pushed twice, and will eventually result in an overflow.

Work around

Two possible solutions are presented. Other solutions may exist.

1. Enable only high priority interrupts for all sources, both synchronous and asynchronous.
2. If it is necessary to use both high and low interrupt priorities:
 - Assign asynchronous interrupts as low priority only.

Note: This does not apply to the INTO (external) interrupt as it is always configured as a high priority interrupt.

- Assign synchronous interrupts to both high and low priority, as needed.

Date Codes that pertain to this issue:

All engineering and production devices.

5. Module: Core (Program Memory Space)

Performing table read operations above the user program memory space (addresses over 1FFFFFFh) may yield erroneous results at the extreme low end of the device's rated temperature range (-40°C).

This applies specifically to addresses above 1FFFFFFh, including the user ID locations (200000h-200007h), the configuration bytes (300000h-30000Dh) and the device ID locations (3FFFFFFh and 3FFFFFFh). User program memory is unaffected.

Work around

Three possible work arounds are presented. Other solutions may exist.

1. Do not perform table read operations on areas above the user memory space at -40°C.
2. Insert NOP instructions (specifically, literal FFFFh) around any table read instructions. The suggested optimal number is 4 instructions before and 8 instructions after each table read. This may vary depending upon the particular application and should be optimized by the user.

Date Codes that pertain to this issue:

All engineering and production devices.

6. Module: Core (Program Memory Space)

Note: This issue applies **only** to PIC18F252 and PIC18F452 devices with 32K words of Flash program memory. PIC18F242 and PIC18F442 devices are **not** affected.

Under certain conditions, the execution of a table read instruction may yield erroneous results. This has been observed when a table read instruction and its read destination, as indicated by the Table Pointer registers, are on opposite sides of the 4000h program memory address boundary.

This behavior has not been observed when the instruction and its target both occur strictly within the same half of the program memory space.

Work around

Insert a data word of value FFFFh immediately following any table read instruction. This behaves as a NOP instruction when executed. Using the actual NOP instruction instead of a literal FFFFh may not have the same results.

This is a recommended solution. Others may exist.

Date Codes that pertain to this issue:

All engineering samples and devices with date codes up to and including 0252 (Year 2002, Work Week 52).

7. Module: Core (Program Memory Space)

Note: This issue applies **only** to PIC18F252 and PIC18F452 devices with 32K words of Flash program memory. PIC18F242 and PIC18F442 devices are **not** affected.

Under certain conditions, the execution of some control operations may yield unexpected results. This has been observed when any of the following instructions vector code execution across the 4000h program memory address boundary:

- CALL
- GOTO
- RETURN
- RETLW
- RETFIE

In addition, unexpected operation may result when an interrupt causes the device to jump across the 4000h boundary to the appropriate interrupt vector.

There are no known issues related to any of these instructions when execution occurs strictly above or below the 4000h address boundary.

Work around

Three possible solutions are presented. Others may exist. It is recommended to implement any one, or any combination of the three, as needed.

1. Insert a data word of value FFFFh as the first instruction in the destination of a CALL or GOTO.
2. Insert a data word of FFFFh at the interrupt vector address(es) (0008h and/or 0018h).
3. Insert a data word of value FFFFh immediately following any RETURN, RETLW, or RETFIE instruction.

In each of these instances, the literal data behaves as a NOP instruction when executed. Using the actual NOP instruction instead of a literal FFFFh may not have the same results.

Date Codes that pertain to this issue:

All engineering samples and devices with date codes up to and including 0252 (Year 2002, Work Week 52).

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8. Module: Data EEPROM

When reading the data EEPROM, the contents of the EEDATA register may be corrupted if the RD bit (EECON1<0>) is set immediately following a write to the address byte (EEADR). The actual contents of the data EEPROM remain unaffected.

Work around

Do not set EEADR immediately before the execution of a read. Write to EEADR at least one instruction cycle before setting the RD bit. The instruction between the write to EEADR and the read can be any valid instruction, including a NOP.

Date Codes that pertain to this issue:

All engineering and production devices.

9. Module: MSSP (All I²C™ and SPI™ Modes)

The Buffer Full (BF) flag bit of the SSPSTAT register (SSPSTAT<0>) may be inadvertently cleared even when the SSPBUF register has not been read. This will occur only when the following two conditions occur simultaneously:

- The four Least Significant bits of the BSR register are equal to 0Fh (BSR<3:0> = 1111) and
- Any instruction that contains C9h in its 8 Least Significant bits (i.e., register file addresses, literal data, address offsets, etc.) is executed.

Work around

All work arounds will involve setting the contents of BSR<3:0> to some value other than 0Fh.

In addition to those proposed below, other solutions may exist.

1. When developing or modifying code, keep these guidelines in mind:
 - Assign 12-bit addresses to all variables. This allows the assembler to know when Access Banking can be used.
 - Do not set the BSR to point to Bank 15 (BSR = 0Fh).
 - Allow the assembler to manipulate the access bit present in most instructions. Accessing the SFRs in Bank 15 will be done through the Access Bank. Continue to use the BSR to select all GPR Banks.
2. If accessing a part of Bank 15 is required and the use of Access Banking is not possible, consider using indirect addressing.
3. If pointing the BSR to Bank 15 is unavoidable, review the absolute file listing. Verify that no instructions contain C9h in the 8 Least Significant bits while the BSR points to Bank 15 (BSR = 0Fh).

Date Codes that pertain to this issue:

All engineering and production devices.

10. Module: MSSP (SPI, Slave Mode)

In its current implementation, the \overline{SS} (Slave Select) control signal, generated by an external master processor, may not be successfully recognized by the PIC® microcontroller operating in Slave Select mode (SSPM3:SSPM0 = 0100). In particular, it has been observed that faster transitions (those with shorter fall times) are more likely to be missed than slower transitions.

Work around

Insert a series resistor between the source of the \overline{SS} signal and the corresponding \overline{SS} input line of the microcontroller. The value of the resistor is dependent on both the application system's characteristics and process variations between microcontrollers. Experimentation and thorough testing is encouraged.

This is a recommended solution. Others may exist.

Date Codes that pertain to this issue:

All engineering and production devices.

11. Module: Core (Instruction Set)

The Decimal Adjust W register instruction, DAW, may improperly clear the Carry bit (STATUS<0>) when executed.

Work around

Test the Carry bit state before executing the DAW instruction. If the Carry bit is set, increment the next higher byte to be added using an instruction such as INCF SZ (this instruction does not affect any Status flags, and will not overflow a BCD nibble). After the DAW instruction has been executed, process the Carry bit normally (see Example 2).

EXAMPLE 2: PROCESSING THE CARRY BIT DURING BCD ADDITIONS

```
MOVLW 0x80      ; .80 (BCD)
ADDLW 0x80      ; .80 (BCD)

BTFSC STATUS,C  ; test C
INCFSZ byte2    ; inc next higher LSB
DAW
BTFSC STATUS,C  ; test C
INCFSZ byte2    ; inc next higher LSB

This is repeated for each DAW instruction.
```

12. Module: Timer1 Oscillator

After the system clock source for the microcontroller is switched from the primary oscillator to the Timer1 oscillator, an increase in system current consumption may occur.

Work around

None

Date Codes that pertain to this issue:

All engineering and production devices.

13. Module: Reset

It has been observed that in certain Reset conditions, including power-up, the first `GOTO` instruction at address 0x0000 may not be executed. This occurrence is rare and affects very few applications.

To determine if your system is affected, test a statistically significant number of applications across the operating temperature, voltage and frequency ranges of the application. Affected systems will repeatably fail normal testing. Systems not affected will continue to not be affected over time.

Work around

Insert a `NOP` instruction at address 0x0000.

Date Codes that pertain to this issue:

All engineering and production devices.

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Clarifications/Corrections to the Data Sheet:

In the Device Data Sheet (DS39564B), the following clarifications and corrections should be noted.

1. Module: DC Characteristics

Some of the maximum values for parameters D022A and D022B shown in **Section 22.1 “DC Characteristics”** of the Device Data Sheet have changed (modified text in bold):

22.1 DC Characteristics: PIC18FXX2 (Industrial, Extended) PIC18LFXX2 (Industrial)

PIC18LFXX2 (Industrial)		Standard Operating Conditions (unless otherwise stated) Operating temperature $-40^{\circ}\text{C} \leq T_A \leq +85^{\circ}\text{C}$ for industrial					
PIC18FXX2 (Industrial, Extended)		Standard Operating Conditions (unless otherwise stated) Operating temperature $-40^{\circ}\text{C} \leq T_A \leq +85^{\circ}\text{C}$ for industrial $-40^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ for extended					
Param No.	Symbol	Characteristic	Min	Typ	Max	Units	Conditions
Module Differential Current							
D022A	ΔI_{BOR}	Brown-out Reset PIC18LFXX2	—	29	40	μA	$V_{DD} = 2.0\text{V}, +25^{\circ}\text{C}$
			—	29	45	μA	$V_{DD} = 2.0\text{V}, -40^{\circ}\text{C to } +85^{\circ}\text{C}$
			—	33	50	μA	$V_{DD} = 4.2\text{V}, -40^{\circ}\text{C to } +85^{\circ}\text{C}$
D022A		Brown-out Reset PIC18FXX2	—	36	45	μA	$V_{DD} = 4.2\text{V}, +25^{\circ}\text{C}$
			—	36	50	μA	$V_{DD} = 4.2\text{V}, -40^{\circ}\text{C to } +85^{\circ}\text{C}$
			—	36	65	μA	$V_{DD} = 4.2\text{V}, -40^{\circ}\text{C to } +125^{\circ}\text{C}$
D022B	ΔI_{LVD}	Low Voltage Detect PIC18LFXX2	—	29	40	μA	$V_{DD} = 2.0\text{V}, +25^{\circ}\text{C}$
			—	29	45	μA	$V_{DD} = 2.0\text{V}, -40^{\circ}\text{C to } +85^{\circ}\text{C}$
			—	33	50	μA	$V_{DD} = 4.2\text{V}, -40^{\circ}\text{C to } +85^{\circ}\text{C}$
D022B		Low Voltage Detect PIC18FXX2	—	33	45	μA	$V_{DD} = 4.2\text{V}, +25^{\circ}\text{C}$
			—	33	50	μA	$V_{DD} = 4.2\text{V}, -40^{\circ}\text{C to } +85^{\circ}\text{C}$
			—	33	65	μA	$V_{DD} = 4.2\text{V}, -40^{\circ}\text{C to } +125^{\circ}\text{C}$

Legend: Shading of rows is to assist in readability of the table.

Note 1: This is the limit to which VDD can be lowered in Sleep mode, or during a device Reset, without losing RAM data.

- 2:** The supply current is mainly a function of the operating voltage and frequency. Other factors, such as I/O pin loading and switching rate, oscillator type, internal code execution pattern and temperature, also have an impact on the current consumption.

The test conditions for all IDD measurements in active operation mode are:

$\overline{\text{OSC1}}$ = external square wave, from rail-to-rail; all I/O pins tri-stated, pulled to VDD

$\overline{\text{MCLR}} = V_{DD}$; WDT enabled/disabled as specified.

- 3:** The power-down current in Sleep mode does not depend on the oscillator type. Power-down current is measured with the part in Sleep mode, with all I/O pins in high-impedance state and tied to VDD or VSS, and all features that add delta current disabled (such as WDT, Timer1 Oscillator, BOR,...).
- 4:** For RC oscillator configuration, current through REXT is not included. The current through the resistor can be estimated by the formula $I_r = V_{DD}/2R_{EXT}$ (mA) with REXT in k Ω .

2. Module: Packaging (Pinout and Product Identification)

PIC18F442 and PICF452 devices are now offered in 44-pin, near chip-scale micro lead frame packages (commonly known as “QFN”). This packaging type has been added to the product line since the latest revision of the Device Data Sheet.

The addition of this option requires the following additions to the Device Data Sheet (DS39564B). The referenced figures and tables follow this text.

1. The “Pin Diagrams” on pages 2-3 of the Data Sheet are amended with the addition of the 44-pin QFN pinout, shown in Figure 1.
2. Table 1-3 of **Section 1.0 “Overview”** is replaced with an updated version which adds a column for QFN pin assignments. A row is also added for previously unlisted NC pins. All new information is indicated in **bold**.

3. **Section 24.1 “Package Marking Information”** is amended to include a marking template and example for 44-pin QFN devices. These are shown in Figure 1.

4. **Section 24.2 “Package Details”** is amended to include the mechanical drawing of the 44-pin QFN package following the existing drawings. This is shown in Figure 2.

5. In the **“PIC18FXX2 Product Identification System”** (page 329), the “Package” options are amended to include the new line item:

ML = QFN

For the sake of completeness, it is also noted that the package designation “MLF” is now replaced by “QFN” in all occurrences throughout the Device Data Sheet. “MLF” should be considered an obsolete term.

FIGURE 1: PINOUT DIAGRAM FOR 44-PIN QFN PACKAGE

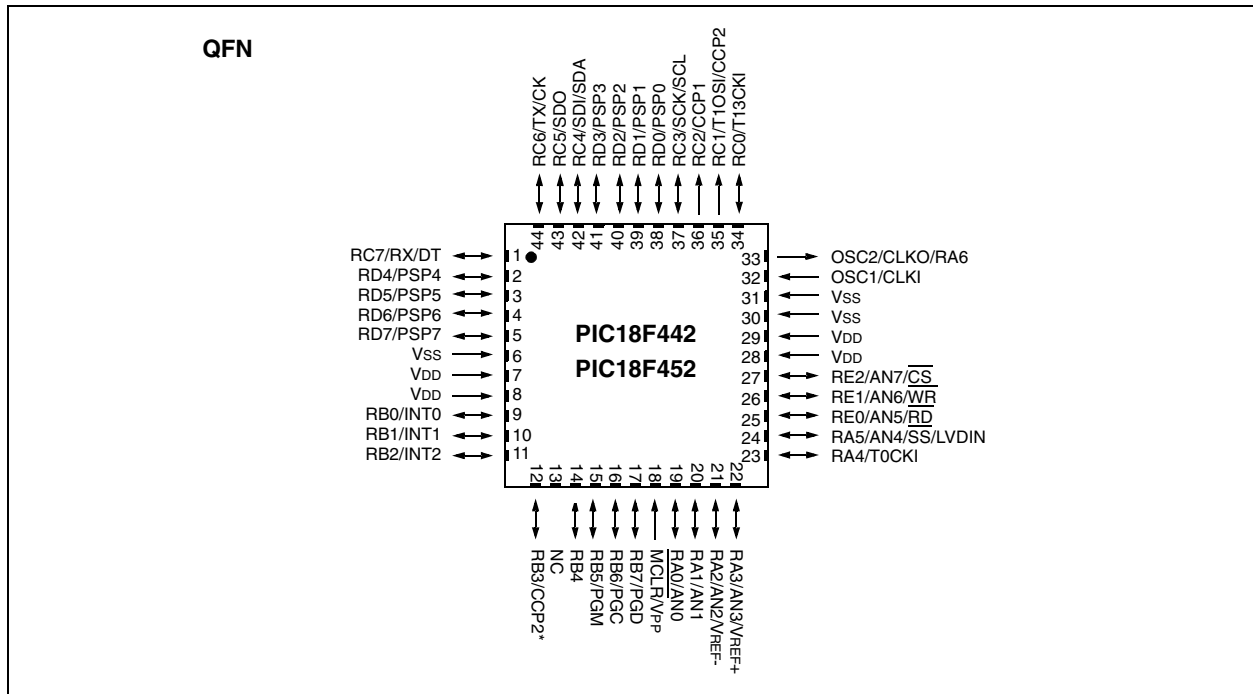


FIGURE 1: PACKAGE MARKING TEMPLATE FOR PIC18F442/452, 44-PIN QFN

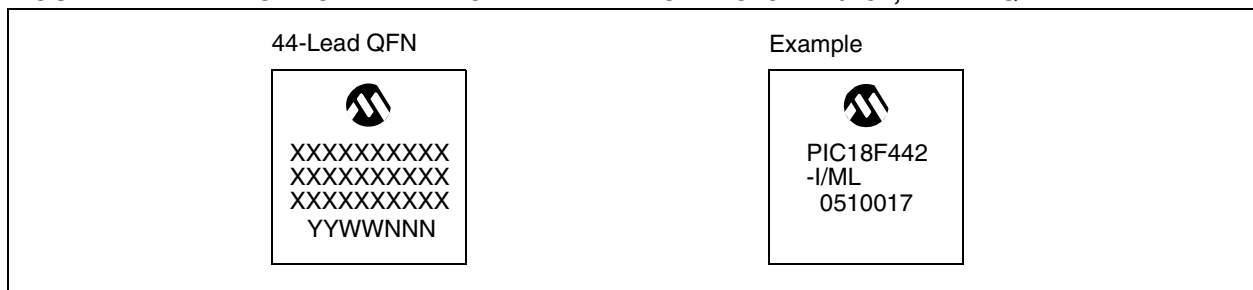


TABLE 1-3: PIC18F4X2 PINOUT I/O DESCRIPTIONS (CONTINUED)

Pin Name	Pin Number				Pin Type	Buffer Type	Description
	DIP	PLCC	QFN	TQFP			
RB0/INT0 RB0 INT0	33	36	9	8	I/O I	TTL ST	PORTB is a bidirectional I/O port. PORTB can be software programmed for internal weak pull-ups on all inputs. Digital I/O. External Interrupt 0.
RB1/INT1 RB1 INT1	34	37	10	9	I/O I	TTL ST	Digital I/O. External Interrupt 1.
RB2/INT2 RB2 INT2	35	38	11	10	I/O I	TTL ST	Digital I/O. External Interrupt 2.
RB3/CCP2 RB3 CCP2	36	39	12	11	I/O I/O	TTL ST	Digital I/O. Capture2 input, Compare2 output, PWM2 output.
RB4	37	41	14	14	I/O	TTL	Digital I/O. Interrupt-on-change pin.
RB5/PGM RB5 PGM	38	42	15	15	I/O I/O	TTL ST	Digital I/O. Interrupt-on-change pin. Low-Voltage ICSP™ Programming enable pin.
RB6/PGC RB6 PGC	39	43	16	16	I/O I/O	TTL ST	Digital I/O. Interrupt-on-change pin. In-Circuit Debugger and ICSP programming clock pin.
RB7/PGD RB7 PGD	40	44	17	17	I/O I/O	TTL ST	Digital I/O. Interrupt-on-change pin. In-Circuit Debugger and ICSP programming data pin.

Legend: TTL = TTL compatible input
 ST = Schmitt Trigger input with CMOS levels
 O = Output
 OD = Open-Drain (no P diode to V_{DD})

CMOS = CMOS compatible input or output
 I = Input
 P = Power

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TABLE 1-3: PIC18F4X2 PINOUT I/O DESCRIPTIONS (CONTINUED)

Pin Name	Pin Number				Pin Type	Buffer Type	Description
	DIP	PLCC	QFN	TQFP			
RC0/T1OSO/T1CKI RC0 T1OSO T1CKI	15	16	34	32	I/O O I	ST — ST	PORTC is a bidirectional I/O port. Digital I/O. Timer1 oscillator output. Timer1/Timer3 external clock input.
RC1/T1OSI/CCP2 RC1 T1OSI CCP2	16	18	35	35	I/O I I/O	ST CMOS ST	Digital I/O. Timer1 oscillator input. Capture2 input, Compare2 output, PWM2 output.
RC2/CCP1 RC2 CCP1	17	19	36	36	I/O I/O	ST ST	Digital I/O. Capture1 input/Compare1 output/ PWM1 output.
RC3/SCK/SCL RC3 SCK SCL	18	20	37	37	I/O I/O I/O	ST ST ST	Digital I/O. Synchronous serial clock input/output for SPI™ mode. Synchronous serial clock input/output for I ² C™ mode.
RC4/SDI/SDA RC4 SDI SDA	23	25	42	42	I/O I I/O	ST ST ST	Digital I/O. SPI Data In. I ² C Data I/O.
RC5/SDO RC5 SDO	24	26	43	43	I/O O	ST —	Digital I/O. SPI Data Out.
RC6/TX/CK RC6 TX CK	25	27	44	44	I/O O I/O	ST — ST	Digital I/O. USART Asynchronous Transmit. USART Synchronous Clock (see related RX/DT).
RC7/RX/DT RC7 RX DT	26	29	1	1	I/O I I/O	ST ST ST	Digital I/O. USART Asynchronous Receive. USART Synchronous Data (see related TX/CK).

Legend: TTL = TTL compatible input
 ST = Schmitt Trigger input with CMOS levels
 O = Output
 OD = Open-Drain (no P diode to VDD)

CMOS = CMOS compatible input or output
 I = Input
 P = Power

TABLE 1-3: PIC18F4X2 PINOUT I/O DESCRIPTIONS (CONTINUED)

Pin Name	Pin Number				Pin Type	Buffer Type	Description
	DIP	PLCC	QFN	TQFP			
RD0/PSP0	19	21	38	38	I/O	ST TTL	PORTD is a bidirectional I/O port, or a Parallel Slave Port (PSP) for interfacing to a microprocessor port. These pins have TTL input buffers when PSP module is enabled. Digital I/O. Parallel Slave Port Data.
RD1/PSP1	20	22	39	39	I/O	ST TTL	
RD2/PSP2	21	23	40	40	I/O	ST TTL	
RD3/PSP3	22	24	41	41	I/O	ST TTL	
RD4/PSP4	27	30	2	2	I/O	ST TTL	
RD5/PSP5	28	31	3	3	I/O	ST TTL	
RD6/PSP6	29	32	4	4	I/O	ST TTL	
RD7/PSP7	30	33	5	5	I/O	ST TTL	
RE0/ $\overline{\text{RD}}$ /AN5 RE0 $\overline{\text{RD}}$	8	9	25	25	I/O	ST TTL	PORTE is a bidirectional I/O port. Digital I/O. Read control for Parallel Slave Port (see also $\overline{\text{WR}}$ and $\overline{\text{CS}}$ pins). Analog input 5.
AN5 RE1/ $\overline{\text{WR}}$ /AN6 RE1 $\overline{\text{WR}}$	9	10	26	26	I/O	Analog ST TTL	
AN6 RE2/ $\overline{\text{CS}}$ /AN7 RE2 $\overline{\text{CS}}$	10	11	27	27	I/O	Analog ST TTL	
AN7						Analog	Analog input 7.
Vss	12, 31	13, 34	6, 30, 31	6, 29	P	—	Ground reference for logic and I/O pins.
VDD	11, 32	12, 35	7, 8, 28, 29	7, 28	P	—	Positive supply for logic and I/O pins.
NC	—	1, 17, 28	13	12, 13, 33, 34	—	—	These pins are not internally connected. They should be left unconnected.

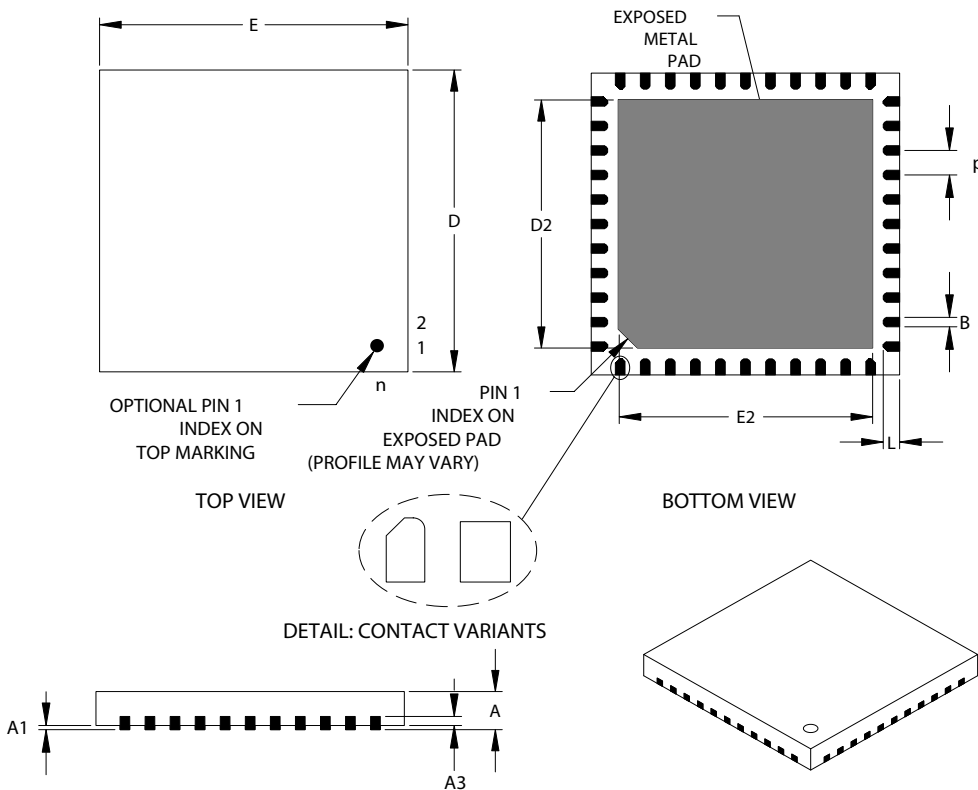
Legend: TTL = TTL compatible input
 ST = Schmitt Trigger input with CMOS levels
 O = Output
 OD = Open-Drain (no P diode to VDD)

CMOS = CMOS compatible input or output
 I = Input
 P = Power

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FIGURE 2: 44-PIN QFN PACKAGE

44-Lead Plastic Quad Flat No Lead Package (ML) 8x8 mm Body (QFN)



Dimension Limits	Units	INCHES			MILLIMETERS*		
		MIN	NOM	MAX	MIN	NOM	MAX
Number of Contacts	n	44			44		
Pitch	p	.026 BSC ¹			0.65 BSC ¹		
Overall Height	A	.031	.035	.039	0.80	0.90	1.00
Standoff	A1	.000	.001	.002	0	0.02	0.05
Base Thickness	A3	.010 REF ²			0.25 REF ²		
Overall Width	E	.309	.315	.321	7.85	8.00	8.15
Exposed Pad Width	E2	.246	.268	.274	6.25	6.80	6.95
Overall Length	D	.309	.315	.321	7.85	8.00	8.15
Exposed Pad Length	D2	.246	.268	.274	6.25	6.80	6.95
Contact Width	B	.008	.013	.013	0.20	0.33	0.35
Contact Length	L	.014	.016	.019	0.35	0.40	0.48

*Controlling Parameter

Notes:

1. BSC: Basic Dimension. Theoretically exact value shown without tolerances. See ASME Y14.5M
2. REF: Reference Dimension, usually without tolerance, for information purposes only. See ASME Y14.5M

JEDEC equivalent: M0-220
Drawing No. C04-103

Revised 3-14-05

3. Module: DC Characteristics

The following parameters in **Section 22.2 “DC Characteristics”** have been updated as follows:

- D032A has been changed and renamed D033
- D033 has been changed and renamed D033A
- D033B has been added
- D042A has been changed and renamed D043
- D043 has been changed and renamed D043A
- D043B has been added.

Changes are shown in **bold** text in the following table.

22.2 DC Characteristics: PIC18FXX2 (Industrial, Extended) PIC18LFXX2 (Industrial)

DC CHARACTERISTICS			Standard Operating Conditions (unless otherwise stated) Operating temperature $-40^{\circ}\text{C} \leq T_A \leq +85^{\circ}\text{C}$ for industrial $-40^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ for extended			
Param No.	Symbol	Characteristic	Min	Max	Units	Conditions
	V_{IL}	Input Low Voltage I/O ports:				
D030		with TTL buffer	V_{SS}	$0.15 V_{DD}$	V	$V_{DD} < 4.5V$
D030A			—	0.8	V	$4.5V \leq V_{DD} \leq 5.5V$
D031		with Schmitt Trigger buffer RC3 and RC4	V_{SS}	$0.2 V_{DD}$	V	
			V_{SS}	$0.3 V_{DD}$	V	
D032		\overline{MCLR}	V_{SS}	$0.2 V_{DD}$	V	
D033		OSC1 (HS mode)	V_{SS}	$0.3 V_{DD}$	V	
D033A		OSC1 (in RC and EC mode) ⁽¹⁾	V_{SS}	$0.2 V_{DD}$	V	
D033B		OSC1 (in XT and LP modes and T1OSI)	V_{SS}	0.3	V	
	V_{IH}	Input High Voltage I/O ports:				
D040		with TTL buffer	$0.25 V_{DD} + 0.8V$	V_{DD}	V	$V_{DD} < 4.5V$
D040A			2.0	V_{DD}	V	$4.5V \leq V_{DD} \leq 5.5V$
D041		with Schmitt Trigger buffer RC3 and RC4	$0.8 V_{DD}$	V_{DD}	V	
			$0.7 V_{DD}$	V_{DD}	V	
D042		\overline{MCLR} , OSC1 (EC mode)	$0.8 V_{DD}$	V_{DD}	V	
D043		OSC1 (HS mode)	$0.7 V_{DD}$	V_{DD}	V	
D043A		OSC1 (RC mode) ⁽¹⁾	$0.9 V_{DD}$	V_{DD}	V	
D043B		OSC1 (in XT and LP modes and T1OSI)	1.6	V_{DD}	V	

Note 1: In RC oscillator configuration, the OSC1/CLKI pin is a Schmitt Trigger input. It is not recommended that the PICmicro® device be driven with an external clock while in RC mode.

2: The leakage current on the \overline{MCLR} pin is strongly dependent on the applied voltage level. The specified levels represent normal operating conditions. Higher leakage current may be measured at different input voltages.

3: Negative current is defined as current sourced by the pin.

4: Parameter is characterized but not tested.

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REVISION HISTORY

Rev A Document (2/2002)

First revision of this document (data sheet issues 1 (Interrupts), 2 and 3 (USART)).

Rev B Document (3/2002)

First silicon specific issues; added issues 1 and 2 (Program Memory).

Rev C Document (3/2002)

Added silicon issue 3 (Data EEPROM) and data sheet issue 4 (Program Memory).

Rev D Document (7/2002)

Added silicon issues 4 and 5 (Interrupts and Core – Program Memory Space).

Rev E Document (10/2002)

All data sheet issues were removed. Added silicon issues 6, 7 and 8 (Core – Program Memory Space and Data EEPROM).

Rev F Document (1/2003)

Added data sheet clarification 1 (DC Characteristics).

Rev G Document (3/2003)

Updated silicon issue 7 (Core – Program Memory Space). Added silicon issues 9, 10 and 11 (MSSP and Core Instruction Set) and data sheet clarification 2 (Packaging – Pinout and Product Identification).

Rev H Document (7/2003)

Added silicon issue 12 (Timer1 Oscillator).

Rev J Document (8/2004)

Updated Data Sheet Clarification issue 2 (Packaging) and added Data Sheet Clarification issue 3 (DC Characteristics).

Rev K Document (05/2005)

Added silicon issue 13 (Reset).

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